

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0001
CB Certificate No.: 50600079 ITL

Schedule Number: IECQ-L ULTW 16.0001-S Rev No.: 2 Revision Date: 2023/02/27 Page 1 of 1

Appendix-1 (50600079 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Hot-Carrier-Induced Degradation Under DC Stress (HCI)	JESD28, JESD60
Negative Bias Temperature Instabilities (NBTI)	JESD90
High Temperature Reverse Bias (HTRB)	JESD22A-108

Date: 2/27/2023

